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Product data sheet

## 1. General description

The PCF8576D is a peripheral device which interfaces to almost any Liquid Crystal Display (LCD) with low multiplex rates. It generates the drive signals for any static or multiplexed LCD containing up to four backplanes and up to 40 segments. It can be easily cascaded for larger LCD applications. The PCF8576D is compatible with most microcontrollers and communicates via the two-line bidirectional $\mathrm{I}^{2} \mathrm{C}$-bus. Communication overheads are minimized by a display RAM with auto-incremented addressing, by hardware subaddressing and by display memory switching (static and duplex drive modes).

## 2. Features and benefits

- AEC-Q100 compliant (PCF8576DT/S400/2) for automotive applications
- Single chip LCD controller and driver
- Selectable backplane drive configuration: static or 2,3, 4 backplane multiplexing
- Selectable display bias configuration: static, $1 / 2$ or $1 / 3$
- Internal LCD bias generation with voltage-follower buffers

■ 40 segment drives:

- Up to 20 7-segment numeric characters
- Up to 10 14-segment alphanumeric characters
- Any graphics of up to 160 elements
- $40 \times 4$-bit RAM for display data storage

■ Auto-incremented display data loading across device subaddress boundaries

- Display memory bank switching in static and duplex drive modes
- Versatile blinking modes

■ Independent supplies possible for LCD and logic voltages
■ Wide power supply range: from 1.8 V to 5.5 V

- Wide logic LCD supply range:
- From 2.5 V for low-threshold LCDs
$\checkmark$ Up to 6.5 V for high-threshold twisted nematic LCDs
- Low power consumption
- $400 \mathrm{kHz} \mathrm{I}^{2} \mathrm{C}$-bus interface
- May be cascaded for large LCD applications (up to 2560 elements possible)
- No external components required
- Compatible with chip-on-glass and chip-on-board technology
- Manufactured in silicon gate CMOS process


## 3. Ordering information

Table 1. Ordering information

| Type number | Package |  |  |
| :---: | :---: | :---: | :---: |
|  | Name | Description | Version |
| PCF8576DT/2 | TSSOP56 | plastic thin shrink small outline package, 56 leads; body width 6.1 mm | SOT364-1 |
| PCF8576DT/S400/2 | TSSOP56 | plastic thin shrink small outline package, 56 leads; body width 6.1 mm | SOT364-1 |
| PCF8576DU/DA/2 | wire bond die | 59 bonding pads[1] | PCF8576DU/DA |
| PCF8576DU/2DA/2 | bare die | 59 bumps[ ${ }^{[2]}$ | PCF8576DU/2DA |
| [1] Chips in tray. |  |  |  |
| [2] Chips with bumps in | tray. |  |  |

## 4. Marking

Table 2. Marking codes

| Type number | Marking code |
| :--- | :--- |
| PCF8576DT/2 | PCF8576DT |
| PCF8576DT/S400/2 | PCF8576DT/S400 |
| PCF8576DU/DA/2 | PC8576D-2 |
| PCF8576DU/2DA/2 | PC8576D-2 |

## 5. Block diagram



Fig 1. Block diagram of PCF8576D

## 6. Pinning information

### 6.1 Pinning



Top view. For mechanical details, see Figure 24
Fig 2. Pinning diagram for PCF8576DT/x (TSSOP56)

Viewed from active side. C1 and C2 are alignment marks. For mechanical details, see Figure 25 and Figure 26.

Fig 3. Pinning diagram for PCF8576DU/x (bare die)

### 6.2 Pin description

Table 3. Pin description

| Symbol | Pin |  | Description |
| :---: | :---: | :---: | :---: |
|  | PCF8576DT/x | PCF8576DU/x |  |
| SDA | 44 | 1,58, 59 | $1^{2} \mathrm{C}$-bus serial data input and output |
| SCL | 45 | 2, 3 | $1^{2} \mathrm{C}$-bus serial clock input |
| CLK | 47 | 5 | external clock input or output |
| $V_{\text {DD }}$ | 48 | 6 | supply voltage |
| $\overline{\text { SYNC }}$ | 46 | 4 | cascade synchronization input or output |
| OSC | 49 | 7 | internal oscillator enable input |
| A0 to A2 | 50 to 52 | 8 to 10 | subaddress inputs |
| SAO | 53 | 11 | $1^{2} \mathrm{C}$-bus address input; bit 0 |
| $\mathrm{V}_{\text {SS }}$ | 54 | 12[1] | ground supply voltage |
| $V_{\text {LCD }}$ | 55 | 13 | LCD supply voltage |
| $\begin{aligned} & \mathrm{BPO}, \mathrm{BP} 2, \\ & \mathrm{BP} 1, \mathrm{BP} 3 \end{aligned}$ | 56, 1, 2, 3 | 14 to 17 | LCD backplane outputs |
| S0 to S39 | 4 to 43 | 18 to 57 | LCD segment outputs |
| n.c. | - | - | not connected |

[1] The substrate (rear side of the die) is connected to $\mathrm{V}_{\mathrm{SS}}$ and should be electrically isolated.

## 7. Functional description

The PCF8576D is a versatile peripheral device designed to interface any microprocessor or microcontroller with a wide variety of LCDs. It can directly drive any static or multiplexed LCD containing up to four backplanes and up to 40 segments.

The possible display configurations of the PCF8576D depend on the number of active backplane outputs required. A selection of display configurations is shown in Table 4. All of these configurations can be implemented in the typical system shown in Figure 4.

Table 4. Selection of possible display configurations

| Number of |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Backplanes | Icons | Digits/Characters |  | Dot matrix/ Elements |
|  |  | 7-segment | 14-segment |  |
| 4 | 160 | 20 | 10 | $160(4 \times 40)$ |
| 3 | 120 | 15 | 7 | $120(3 \times 40)$ |
| 2 | 80 | 10 | 5 | $80(2 \times 40)$ |
| 1 | 40 | 5 | 2 | $40(1 \times 40)$ |



The resistance of the power lines must be kept to a minimum.
For chip-on-glass applications, due to the Indium Tin Oxide (ITO) track resistance, each supply line must be routed separately between the chip and the connector

Fig 4. Typical system configuration
The host microprocessor or microcontroller maintains the 2-line $\mathrm{I}^{2} \mathrm{C}$-bus communication channel with the PCF8576D. The internal oscillator is enabled by connecting pin OSC to pin $V_{\text {Ss }}$. The appropriate biasing voltages for the multiplexed LCD waveforms are generated internally. The only other connections required to complete the system are to the power supplies ( $\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{SS}}$ and $\mathrm{V}_{\mathrm{LCD}}$ ) and the LCD panel chosen for the application.

### 7.1 Power-on reset

At power-on the PCF8576D resets to the following starting conditions:

- All backplane outputs are set to $\mathrm{V}_{\mathrm{LCD}}$
- All segment outputs are set to $V_{\text {LCD }}$
- The selected drive mode is: 1:4 multiplex with $1 / 3$ bias
- Blinking is switched off
- Input and output bank selectors are reset
- The $I^{2} \mathrm{C}$-bus interface is initialized
- The data pointer and the subaddress counter are cleared (set to logic 0)
- Display is disabled

Data transfers on the $I^{2} \mathrm{C}$-bus must be avoided for 1 ms following power-on to allow the reset action to complete.

### 7.2 LCD bias generator

Fractional LCD biasing voltages are obtained from an internal voltage divider consisting of three impedances connected in series between $\mathrm{V}_{\mathrm{LCD}}$ and $\mathrm{V}_{\mathrm{SS}}$. The middle resistor can be bypassed to provide a $1 / 2$ bias voltage level for the $1: 2$ multiplex configuration. The LCD voltage can be temperature compensated externally using the supply to pin $\mathrm{V}_{\mathrm{LCD}}$.

### 7.3 LCD voltage selector

The LCD voltage selector coordinates the multiplexing of the LCD in accordance with the selected LCD drive configuration. The operation of the voltage selector is controlled by the mode-set command (see Table 9) from the command decoder. The biasing configurations that apply to the preferred modes of operation, together with the biasing characteristics as functions of $\mathrm{V}_{\mathrm{LCD}}$ and the resulting discrimination ratios (D), are given in Table 5.

Table 5. Discrimination ratios

| LCD drive <br> mode | Number of: |  | LCD bias |  |  |  |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
|  | Backplanes | Levels |  | $V_{\text {off }(R M S)}$ | $\frac{V_{o n(R M S)}}{V_{L C D}}$ | $D=\frac{V_{o n(R M S)}}{V_{o f f(R M S)}}$ |
| static | 1 | 2 | static | 0 | 1 | $\infty$ |
| $1: 2$ multiplex | 2 | 3 | $1 / 2$ | 0.354 | 0.791 | 2.236 |
| $1: 2$ multiplex | 2 | 4 | $1 / 3$ | 0.333 | 0.745 | 2.236 |
| $1: 3$ multiplex | 3 | 4 | $1 / 3$ | 0.333 | 0.638 | 1.915 |
| $1: 4$ multiplex | 4 | 4 | $1 / 3$ | 0.333 | 0.577 | 1.732 |

A practical value for $\mathrm{V}_{\mathrm{LCD}}$ is determined by equating $\mathrm{V}_{\text {off( } \mathrm{RMS})}$ with a defined LCD threshold voltage ( $\mathrm{V}_{\text {th }}$ ), typically when the LCD exhibits approximately $10 \%$ contrast. In the static drive mode a suitable choice is $\mathrm{V}_{\mathrm{LCD}}>3 \mathrm{~V}_{\text {th }}$.

Multiplex drive modes of 1:3 and 1:4 with $1 / 2$ bias are possible but the discrimination and hence the contrast ratios are smaller.

Bias is calculated by $\frac{1}{1+a}$, where the values for a are

$$
\begin{aligned}
& a=1 \text { for } 1 / 2 \text { bias } \\
& a=2 \text { for } 1 / 3 \text { bias }
\end{aligned}
$$

The RMS on-state voltage ( $\left.\mathrm{V}_{\mathrm{on}(\mathrm{RMS})}\right)$ for the LCD is calculated with Equation 1

$$
\begin{equation*}
V_{o n(R M S)}=V_{L C D} \sqrt{\frac{a^{2}+2 a+n}{n \times(1+a)^{2}}} \tag{1}
\end{equation*}
$$

where the values for n are
$\mathrm{n}=1$ for static mode
$\mathrm{n}=2$ for 1:2 multiplex
$\mathrm{n}=3$ for 1:3 multiplex
$\mathrm{n}=4$ for 1:4 multiplex
The RMS off-state voltage $\left(\mathrm{V}_{\text {off( } \mathrm{RMS})}\right)$ for the LCD is calculated with Equation 2:

$$
\begin{equation*}
V_{o f f(R M S)}=V_{L C D} \sqrt{\frac{a^{2}-2 a+n}{n \times(1+a)^{2}}} \tag{2}
\end{equation*}
$$

Discrimination is the ratio of $\mathrm{V}_{\mathrm{on}(\mathrm{RMS})}$ to $\mathrm{V}_{\text {off(RMS) }}$ and is determined from Equation 3:
$D=\frac{V_{o n(R M S)}}{V_{o f f(R M S)}}=\sqrt{\frac{(a+1)^{2}+(n-1)}{(a-1)^{2}+(n-1)}}$
Using Equation 3, the discrimination for an LCD drive mode of 1:3 multiplex with $1 / 2$ bias is $\sqrt{3}=1.732$ and the discrimination for an LCD drive mode of 1:4 multiplex with
$1 / 2$ bias is $\frac{\sqrt{21}}{3}=1.528$.
The advantage of these LCD drive modes is a reduction of the LCD full scale voltage $\mathrm{V}_{\mathrm{LCD}}$ as follows:

- $1: 3$ multiplex ( $1 / 2$ bias): $V_{L C D}=\sqrt{6} \times V_{\text {off }(R M S)}=2.449 V_{\text {off }(R M S)}$
- 1:4 multiplex ( $1 / 2$ bias $): V_{L C D}=\left[\frac{(4 \times \sqrt{3})}{3}\right]=2.309 V_{\text {off(RMS })}$

These compare with $V_{L C D}=3 V_{\text {off(RMS) }}$ when $1 / 3$ bias is used.
It should be noted that $\mathrm{V}_{\mathrm{LCD}}$ is sometimes referred as the LCD operating voltage.

### 7.3.1 Electro-optical performance

Suitable values for $\mathrm{V}_{\text {on(RMS) }}$ and $\mathrm{V}_{\text {off(RMS) }}$ are dependant on the LCD liquid used. The RMS voltage, at which a pixel will be switched on or off, determine the transmissibility of the pixel.

For any given liquid, there are two threshold values defined. One point is at $10 \%$ relative transmission (at $\mathrm{V}_{\text {low }}$ ) and the other at $90 \%$ relative transmission (at $\mathrm{V}_{\text {high }}$ ), see Figure 5. For a good contrast performance, the following rules should be followed:

$$
\begin{align*}
& V_{\text {on }(R M S)} \geq V_{\text {high }}  \tag{4}\\
& V_{\text {off }(R M S)} \leq V_{\text {low }} \tag{5}
\end{align*}
$$

$\mathrm{V}_{\text {on(RMS) }}$ and $\mathrm{V}_{\text {off(RMS) }}$ are properties of the display driver and are affected by the selection of $\mathrm{a}, \mathrm{n}$ (see Equation 1 to Equation 3) and the $\mathrm{V}_{\mathrm{LCD}}$ voltage.
$\mathrm{V}_{\text {low }}$ and $\mathrm{V}_{\text {high }}$ are properties of the LCD liquid and can be provided by the module manufacturer.

It is important to match the module properties to those of the driver in order to achieve optimum performance.


Fig 5. Electro-optical characteristic: relative transmission curve of the liquid

### 7.4 LCD drive mode waveforms

### 7.4.1 Static drive mode

The static LCD drive mode is used when a single backplane is provided in the LCD. The backplane ( BPn ) and segment drive $\left(\mathrm{S}_{\mathrm{n}}\right)$ waveforms for this mode are shown in Figure 6.

(1) $V_{\text {state1 }}(t)=V_{S n}(t)-V_{B P 0}(t)$.
(2) $V_{\text {on(RMS) }}=V_{\text {LCD }}$.
(3) $V_{\text {state2 }}(\mathrm{t})=\mathrm{V}_{\mathrm{Sn+1}}(\mathrm{t})-\mathrm{V}_{\mathrm{BPO}}(\mathrm{t})$.
(4) $V_{\text {off(RMS) }}=0 \mathrm{~V}$.

Fig 6. Static drive mode waveforms

### 7.4.2 1:2 Multiplex drive mode

The 1:2 multiplex drive mode is used when two backplanes are provided in the LCD. This mode allows fractional LCD bias voltages of $1 / 2$ bias or $1 / 3$ bias as shown in Figure 7 and Figure 8.

(1) $\mathrm{V}_{\text {state1 }}(\mathrm{t})=\mathrm{V}_{\mathrm{Sn}}(\mathrm{t})-\mathrm{V}_{\mathrm{BPO}}(\mathrm{t})$.
(2) $\mathrm{V}_{\mathrm{on}(\mathrm{RMS})}=0.791 \mathrm{~V}_{\mathrm{LCD}}$.
(3) $\mathrm{V}_{\text {state2 }}(\mathrm{t})=\mathrm{V}_{\mathrm{Sn}+1}(\mathrm{t})-\mathrm{V}_{\mathrm{BP} 1}(\mathrm{t})$.
(4) $\mathrm{V}_{\text {off }}(\mathrm{RMS})=0.354 \mathrm{~V}_{\mathrm{LCD}}$.

Fig 7. Waveforms for the $1: 2$ multiplex drive mode with $1 / 2$ bias

(1) $\mathrm{V}_{\text {state } 1}(\mathrm{t})=\mathrm{V}_{\mathrm{Sn}}(\mathrm{t})-\mathrm{V}_{\mathrm{BPO}}(\mathrm{t})$.
(2) $V_{\text {on(RMS }}=0.745 V_{\text {LCD }}$.
(3) $\mathrm{V}_{\text {state2 }}(\mathrm{t})=\mathrm{V}_{\mathrm{Sn}+1}(\mathrm{t})-\mathrm{V}_{\mathrm{BP} 1}(\mathrm{t})$.
(4) $\mathrm{V}_{\text {off( } \mathrm{RMS} \text { ) }}=0.333 \mathrm{~V}_{\mathrm{LCD}}$.

Fig 8. Waveforms for the 1:2 multiplex drive mode with $1 / 3$ bias

### 7.4.3 1:3 Multiplex drive mode

When three backplanes are provided in the LCD, the 1:3 multiplex drive mode applies (see Figure 9).


Fig 9. Waveforms for the 1:3 multiplex drive mode with $1 / 3$ bias

### 7.4.4 1:4 Multiplex drive mode

When four backplanes are provided in the LCD, the 1:4 multiplex drive mode applies (see Figure 10).


Fig 10. Waveforms for the $1: 4$ multiplex drive mode with $1 / 3$ bias

### 7.5 Oscillator

### 7.5.1 Internal clock

The internal logic of the PCF8576D and its LCD drive signals are timed either by its internal oscillator or by an external clock. The internal oscillator is enabled by connecting pin OSC to pin $\mathrm{V}_{\text {Ss }}$. If the internal oscillator is used, the output from pin CLK can be used as the clock signal for several PCF8576Ds in the system that are connected in cascade.

### 7.5.2 External clock

Pin CLK is enabled as an external clock input by connecting pin OSC to $\mathrm{V}_{\mathrm{DD}}$.
The LCD frame signal frequency is determined by the clock frequency ( $\mathrm{f}_{\mathrm{clk}}$ ).
Remark: A clock signal must always be supplied to the device; removing the clock may freeze the LCD in a DC state, which is not suitable for the liquid crystal.

### 7.6 Timing

The PCF8576D timing controls the internal data flow of the device. This includes the transfer of display data from the display RAM to the display segment outputs. In cascaded applications, the correct timing relationship between each PCF8576D in the system is maintained by the synchronization signal at pin $\overline{\text { SYNC }}$. The timing also generates the LCD frame signal whose frequency is derived from the clock frequency. The frame signal frequency is a fixed division of the clock frequency from either the internal or an external clock: $f_{f r}=\frac{f_{c l k}}{24}$.

### 7.7 Display register

The display latch holds the display data while the corresponding multiplex signals are generated. There is a one-to-one relationship between the data in the display latch, the LCD segment outputs and each column of the display RAM.

### 7.8 Segment outputs

The LCD drive section includes 40 segment outputs S 0 to S 39 which should be connected directly to the LCD. The segment output signals are generated in accordance with the multiplexed backplane signals and with data residing in the display latch. When less than 40 segment outputs are required, the unused segment outputs should be left open-circuit.

### 7.9 Backplane outputs

The LCD drive section includes four backplane outputs BPO to BP3 which must be connected directly to the LCD. The backplane output signals are generated in accordance with the selected LCD drive mode. If less than four backplane outputs are required, the unused outputs can be left open-circuit

In the 1:3 multiplex drive mode, BP3 carries the same signal as BP1, therefore these two adjacent outputs can be tied together to give enhanced drive capabilities.

In the 1:2 multiplex drive mode, BP0 and BP2, BP1 and BP3 all carry the same signals and may also be paired to increase the drive capabilities.

In the static drive mode the same signal is carried by all four backplane outputs and they can be connected in parallel for very high drive requirements.

### 7.10 Display RAM

The display RAM is a static $40 \times 4$-bit RAM which stores LCD data. A logic 1 in the RAM bit-map indicates the on-state of the corresponding LCD element; similarly, a logic 0 indicates the off-state. There is a one-to-one correspondence between the RAM addresses and the segment outputs, and between the individual bits of a RAM word and the backplane outputs. The display RAM bit map Figure 11 shows the rows 0 to 3 which correspond with the backplane outputs BPO to BP3, and the columns 0 to 39 which correspond with the segment outputs S0 to S39. In multiplexed LCD applications the segment data of the first, second, third and fourth row of the display RAM are time-multiplexed with BP0, BP1, BP2 and BP3 respectively.

## display RAM addresses (columns)/segment outputs (S)



Display RAM bit map showing direct relationship between RAM addresses and segment outputs also between bits in a RAM word and the backplane outputs.

Fig 11. Display RAM bit map
When display data is transmitted to the PCF8576D, the display bytes received are stored in the display RAM in accordance with the selected LCD drive mode. The data is stored as it arrives and does not wait for an acknowledge cycle as with the commands. Depending on the current multiplex drive mode, data is stored singularly, in pairs, triplets or quadruplets. To illustrate the filling order, an example of a 7 -segment numeric display showing all drive modes is given in Figure 12; the RAM filling organization depicted applies equally to other LCD types.

$x=$ data bit unchanged.
Fig 12. Relationship between LCD layout, drive mode, display RAM filling order and display data transmitted over the $I^{2} C$-bus

The following applies to Figure 12:

- In the static drive mode, the eight transmitted data bits are placed in row 0 of eight successive 4-bit RAM words.
- In the 1:2 multiplex mode, the eight transmitted data bits are placed in pairs into row 0 and 1 of four successive 4-bit RAM words.
- In the 1:3 multiplex mode, the eight bits are placed in triples into row 0, 1 and 2 to three successive 4-bit RAM words, with bit 3 of the third address left unchanged. It is not recommended to use this bit in a display because of the difficult addressing. This last bit may, if necessary, be controlled by an additional transfer to this address but care should be taken to avoid overwriting adjacent data because always full bytes are transmitted.
- In the 1:4 multiplex mode, the eight transmitted data bits are placed in quadruples into row 0, 1, 2 and 3 of two successive 4-bit RAM words.


### 7.11 Data pointer

The addressing mechanism for the display RAM is realized using the data pointer.
This allows the loading of an individual display data byte, or a series of display data bytes, into any location of the display RAM. The sequence commences with the initialization of the data pointer by the load-data-pointer command (see Section 7.17).

Following this command, an arriving data byte is stored at the display RAM address indicated by the data pointer. The filling order is shown in Figure 12.

After each byte is stored, the content of the data pointer is automatically incremented by a value dependent on the selected LCD drive mode:

After each byte is stored, the contents of the data pointer is automatically incremented by a value dependent on the selected LCD drive mode:

- In static drive mode by eight
- In 1:2 multiplex drive mode by four
- In 1:3 multiplex drive mode by three
- In 1:4 multiplex drive mode by two

If an $I^{2} \mathrm{C}$-bus data access is terminated early then the state of the data pointer is unknown. The data pointer should be re-written prior to further RAM accesses.

### 7.12 Subaddress counter

The storage of display data is determined by the contents of the subaddress counter. Storage is allowed to take place only when the contents of the subaddress counter match with the hardware subaddress applied to A0, A1 and A2. The subaddress counter value is defined by the device-select command (see Section 7.17). If the contents of the subaddress counter and the hardware subaddress do not match then data storage is inhibited but the data pointer is incremented as if data storage had taken place. The subaddress counter is also incremented when the data pointer overflows.

The storage arrangements described lead to extremely efficient data loading in cascaded applications. When a series of display bytes are sent to the display RAM, automatic wrap-over to the next PCF8576D occurs when the last RAM address is exceeded. Subaddressing across device boundaries is successful even if the change to the next device in the cascade occurs within a transmitted character (such as during the $14^{\text {th }}$ display data byte transmitted in 1:3 multiplex mode).

The hardware subaddress must not be changed while the device is being accessed on the ${ }^{2} \mathrm{C}$-bus interface.

### 7.13 Output bank selector

The output bank selector selects one of the four bits per display RAM address for transfer to the display latch. The actual bit chosen depends on the selected LCD drive mode in operation and on the instant in the multiplex sequence.

- In 1:4 mode, all RAM addresses of bit 0 are selected, these are followed by the contents of bit 1, bit 2 and then bit 3.
- In 1:3 mode, bits 0,1 and 2 are selected sequentially
- In 1:2 mode, bits 0 and 1 are selected
- In static mode, bit 0 is selected

The PCF8576D includes a RAM bank switching feature in the static and 1:2 drive modes. In the static drive mode, the bank-select command (see Section 7.17 ) may request the contents of bit 2 to be selected for display instead of the contents of bit 0 . In 1:2 mode, the contents of bits 2 and 3 may be selected instead of bits 0 and 1 . This gives the provision for preparing display information in an alternative bank and to be able to switch to it once it is assembled.

### 7.14 Input bank selector

The input bank selector loads display data into the display RAM in accordance with the selected LCD drive configuration.

The bank-select command (see Section 7.17) can be used to load display data in bit 2 in static drive mode or in bits 2 and 3 in 1:2 mode. The input bank selector functions are independent of the output bank selector.

### 7.15 Blinker

The PCF8576D has a very versatile display blinking capability. The whole display can blink at a frequency selected by the blink-select command (see Section 7.17). Each blink frequency is a fraction of the clock frequency; the ratio between the clock frequency and blink frequency depends on the blink mode selected (see Table 6).

An additional feature allows an arbitrary selection of LCD segments to blink in the static and 1:2 drive modes. This is implemented without any communication overheads by the output bank selector which alternates the displayed data between the data in the display RAM bank and the data in an alternative RAM bank at the blink frequency. This mode can also be implemented by the blink-select command (see Section 7.17).

In the 1:3 and 1:4 drive modes, where no alternative RAM bank is available, groups of LCD segments can blink selectively by changing the display RAM data at fixed time intervals.

The entire display can blink at a frequency other than the nominal blink frequency by sequentially resetting and setting the display enable bit $E$ at the required rate using the mode-set command (see Section 7.17).

Table 6. Blinking frequencies ${ }^{[1]}$

| Blink mode | Normal operating mode ratio | Nominal blink frequency |
| :--- | :--- | :--- |
| off | - | blinking off |
| 1 | $\frac{f_{c l k}}{768}$ | 2 Hz |
| 2 | $\frac{f_{c l k}}{1536}$ | 1 Hz |
| 3 | $\frac{f_{c l k}}{3072}$ | 0.5 Hz |

1] Blink modes 1, 2 and 3 and the nominal blink frequencies $0.5 \mathrm{~Hz}, 1 \mathrm{~Hz}$ and 2 Hz correspond to an oscillator frequency ( $\mathrm{f}_{\mathrm{clk}}$ ) of 1536 Hz (see Section 11),

### 7.16 Characteristics of the $I^{2} \mathrm{C}$-bus

The $\mathrm{I}^{2} \mathrm{C}$-bus is for bidirectional, two-line communication between different ICs or modules. The two lines are a Serial DAta line (SDA) and a Serial CLock line (SCL). Both lines must be connected to a positive supply via a pull-up resistor when connected to the output stages of a device. Data transfer may be initiated only when the bus is not busy.

### 7.16.1 Bit transfer

One data bit is transferred during each clock pulse. The data on the SDA line must remain stable during the HIGH period of the clock pulse as changes in the data line at this time will be interpreted as a control signal (see Figure 13).


Fig 13. Bit transfer

### 7.16.2 START and STOP conditions

Both data and clock lines remain HIGH when the bus is not busy.
A HIGH-to-LOW transition of the data line while the clock is HIGH is defined as the START condition-S.

A LOW-to-HIGH transition of the data line while the clock is HIGH is defined as the STOP condition - P (see Figure 14).


Fig 14. Definition of START and STOP conditions

### 7.16.3 System configuration

A device generating a message is a transmitter, a device receiving a message is the receiver. The device that controls the message is the master and the devices which are controlled by the master are the slaves (see Figure 15).


Fig 15. System configuration

### 7.16.4 Acknowledge

The number of data bytes transferred between the START and STOP conditions from transmitter to receiver is unlimited. Each byte of eight bits is followed by an acknowledge cycle.

- A slave receiver which is addressed must generate an acknowledge after the reception of each byte.
- Also a master receiver must generate an acknowledge after the reception of each byte that has been clocked out of the slave transmitter.
- The device that acknowledges must pull-down the SDA line during the acknowledge clock pulse, so that the SDA line is stable LOW during the HIGH period of the acknowledge related clock pulse (set-up and hold times must be taken into consideration).
- A master receiver must signal an end of data to the transmitter by not generating an acknowledge on the last byte that has been clocked out of the slave. In this event the transmitter must leave the data line HIGH to enable the master to generate a STOP condition.

Acknowledgement on the $\mathrm{I}^{2} \mathrm{C}$-bus is shown in Figure 16.


Fig 16. Acknowledgement of the $\mathrm{I}^{2} \mathrm{C}$-bus

### 7.16.5 $\mathrm{I}^{2} \mathrm{C}$-bus controller

The PCF8576D acts as an $\mathrm{I}^{2} \mathrm{C}$-bus slave receiver. It does not initiate $\mathrm{I}^{2} \mathrm{C}$-bus transfers or transmit data to an $I^{2} \mathrm{C}$-bus master receiver. The only data output from the PCF8576D are the acknowledge signals of the selected devices. Device selection depends on the $\mathrm{I}^{2} \mathrm{C}$-bus slave address, on the transferred command data and on the hardware subaddress.

In single device applications, the hardware subaddress inputs A0, A1 and A2 are normally tied to $\mathrm{V}_{\mathrm{SS}}$ which defines the hardware subaddress 0 . In multiple device applications $A 0, A 1$ and $A 2$ are tied to $\mathrm{V}_{\mathrm{SS}}$ or $\mathrm{V}_{\mathrm{DD}}$ in accordance with a binary coding scheme such that no two devices with a common $I^{2} \mathrm{C}$-bus slave address have the same hardware subaddress.

### 7.16.6 Input filters

To enhance noise immunity in electrically adverse environments, RC low-pass filters are provided on the SDA and SCL lines.

### 7.16.7 $\mathrm{I}^{2} \mathrm{C}$-bus protocol

Two $I^{2} \mathrm{C}$-bus slave addresses (0111 000 and 0111001 ) are reserved for the PCF8576D. The least significant bit of the slave address that a PCF8576D will respond to is defined by the level tied to its SA0 input. The PCF8576D is a write-only device and will not respond to a read access. Having two reserved slave addresses allows the following on the same $I^{2} \mathrm{C}$-bus:

- Up to 16 PCF8576Ds for very large LCD applications
- The use of two types of LCD multiplex drive.

The $I^{2} \mathrm{C}$-bus protocol is shown in Figure 17. The sequence is initiated with a START condition (S) from the $I^{2}$ C-bus master which is followed by one of two possible PCF8576D slave addresses available. All PCF8576Ds whose SA0 inputs correspond to bit 0 of the slave address respond by asserting an acknowledge in parallel. This $I^{2} \mathrm{C}$-bus transfer is ignored by all PCF8576Ds whose SA0 inputs are set to the alternative level.


Fig 17. $I^{2} \mathrm{C}$-bus protocol
After an acknowledgement, one or more command bytes follow, that define the status of each addressed PCF8576D.

The last command byte sent is identified by resetting its most significant bit, continuation bit C, (see Figure 18). The command bytes are also acknowledged by all addressed PCF8576D on the bus.


Fig 18. Format of command byte
After the last command byte, one or more display data bytes may follow. Display data bytes are stored in the display RAM at the address specified by the data pointer and the subaddress counter. Both data pointer and subaddress counter are automatically updated and the data directed to the intended PCF8576D device.

An acknowledgement after each byte is asserted only by the PCF8576Ds that are addressed via address lines A0, A1 and A2. After the last display byte, the $I^{2} \mathrm{C}$-bus master asserts a STOP condition (P). Alternately a START may be asserted to restart an $\mathrm{I}^{2} \mathrm{C}$-bus access.

### 7.17 Command decoder

The command decoder identifies command bytes that arrive on the $\mathrm{I}^{2} \mathrm{C}$-bus.
The commands available to the PCF8576D are defined in Table 7.
Table 7. Definition of PCF8576D commands

| Command | Operation Code |  |  |  |  |  |  |  |  |  | Reference |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :---: | :---: |
| Bit | $\mathbf{7}$ | $\mathbf{6}$ | $\mathbf{5}$ | $\mathbf{4}$ | $\mathbf{3}$ | $\mathbf{2}$ | $\mathbf{1}$ | $\mathbf{0}$ |  |  |  |
| mode-set | C | 1 | 0 | $\underline{[1]}$ | E | B | M1 | M0 | Table 9 |  |  |
| load-data-pointer | C | 0 | P5 | P4 | P3 | P2 | P1 | P0 | Table 10 |  |  |
| device-select | C | 1 | 1 | 0 | 0 | A2 | A1 | A0 | Table 11 |  |  |
| bank-select | C | 1 | 1 | 1 | 1 | 0 | I | O | Table 12 |  |  |
| blink-select | C | 1 | 1 | 1 | 0 | A | BF1 | BF0 | Table 13 |  |  |

1] Not used.
All available commands carry a continuation bit C in their most significant bit position as shown in Figure 18. When this bit is set, it indicates that the next byte of the transfer to arrive will also represent a command. If this bit is reset, it indicates that the command byte is the last in the transfer. Further bytes will be regarded as display data (see Table 8).

Table 8. C bit description
\(\left.$$
\begin{array}{llll}\hline \text { Bit } & \text { Symbol } & \text { Value } & \begin{array}{l}\text { Description } \\
7\end{array}
$$ <br>

\hline \& Continue bit\end{array}\right]\)| last control byte in the transfer; next byte will be regarded |
| :--- |
|  |

Table 9. Mode-set command bits description

| Bit | Symbol | Value | Description |
| :---: | :---: | :---: | :---: |
| 7 | C | 0, 1 | see Table 8 |
| 6, 5 | - | 10 | fixed value |
| 4 | - | - | unused |
| 3 | E |  | display status |
|  |  | 0 | disabled (blank) ${ }^{[1]}$ |
|  |  | 1 | enabled |
| 2 | B |  | LCD bias configuration[2] |
|  |  | 0 | $1 / 3$ bias |
|  |  | 1 | $1 / 2$ bias |
| 1 to 0 | M[1:0] |  | LCD drive mode selection |
|  |  | 01 | static; BPO |
|  |  | 10 | 1:2 multiplex; BP0, BP1 |
|  |  | 11 | 1:3 multiplex; BP0, BP1, BP2 |
|  |  | 00 | 1:4 multiplex; BP0, BP1, BP2, BP3 |

[1] The possibility to disable the display allows implementation of blinking under external control.
[2] Not applicable for static drive mode.

Table 10. Load-data-pointer command bits description

| Bit | Symbol | Value | Description |
| :--- | :--- | :--- | :--- |
| 7 | C | 0,1 | see Table 8 |
| 6 | - | 0 | fixed value |
| 5 to 0 | $\mathrm{P}[5: 0]$ | 000000 <br> 100111 | 6 bit binary value, 0 to 39; transferred to the data pointer to <br> define one of forty display RAM addresses |

Table 11. Device-select command bits description

| Bit | Symbol | Value | Description |
| :--- | :--- | :--- | :--- |
| 7 | C | 0,1 | see Table 8 |
| 6 to 3 | - | 1100 | fixed value |
| 2 to 0 | A[2:0] | 000 to 111 | 3 bit binary value, 0 to 7 ; transferred to the subaddress <br> counter to define one of eight hardware subaddresses |

Table 12. Bank-select command bits description

| Bit | Symbol | Value | Description |  |
| :---: | :---: | :---: | :---: | :---: |
|  |  |  | Static | 1:2 multiplex ${ }^{[1]}$ |
| 7 | C | 0, 1 | see Table 8 |  |
| 6 to 2 | - | 11110 | fixed value |  |
| 1 | 1 |  | input bank selection; storage of arriving display data |  |
|  |  | 0 | RAM bit 0 | RAM bits 0 and 1 |
|  |  | 1 | RAM bit 2 | RAM bits 2 and 3 |
| 0 | 0 |  | output bank selection; retrieval of LCD display data |  |
|  |  | 0 | RAM bit 0 | RAM bits 0 and 1 |
|  |  | 1 | RAM bit 2 | RAM bits 2 and 3 |

[1] The bank-select command has no effect in 1:3 and 1:4 multiplex drive modes.

Table 13. Blink-select command bits description

| Bit | Symbol | Value | Description |
| :--- | :--- | :--- | :--- |
| 7 | C | 0,1 | see Table 8 |
| 6 to 3 | - | 1110 | fixed value |
| 2 | A |  | blink mode selection |
|  |  | 0 | normal blinking $\underline{[1]}$ |
| 1 to 0 | $B F[1: 0]$ |  | alternate RAM bank blinking $\underline{[2]}]$ |
|  |  | 00 | blink frequency selection |
|  |  | 01 | 1 |
|  |  | 10 | 2 |
|  |  | 11 | 3 |

[1] Normal blinking is assumed when the LCD multiplex drive modes 1:3 or 1:4 are selected.
[2] Alternate RAM bank blinking does not apply in 1:3 and 1:4 multiplex drive modes.

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| :--- | :---: | :---: |
| Product data sheet | Rev. $10-14$ February 2011 |  |

### 7.18 Display controller

The display controller executes the commands identified by the command decoder. It contains the device's status registers and coordinates their effects. The display controller is also responsible for loading display data into the display RAM in the correct filling order.

## 8. Internal circuitry



Fig 19. Device protection circuits

## 9. Limiting values

## CAUTION



Static voltages across the liquid crystal display can build up when the LCD supply voltage $\left(V_{L C D}\right)$ is on while the IC supply voltage ( $V_{D D}$ ) is off, or vice versa. This may cause unwanted display artifacts. To avoid such artifacts, $\mathrm{V}_{\text {LCD }}$ and $\mathrm{V}_{\mathrm{DD}}$ must be applied or removed together.

Table 14. Limiting values
In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| $V_{\text {DD }}$ | supply voltage |  | -0.5 | 6.5 | V |
| $V_{\text {LCD }}$ | LCD supply voltage |  | -0.5 | +7.5 | V |
| $V_{1}$ | input voltage | on each of the pins CLK, SDA, SCL, $\overline{\text { SYNC, SAO, }}$ OSC, A0 to A2 | -0.5 | +6.5 | V |
| $\mathrm{V}_{0}$ | output voltage | on each of the pins SO to S39, BPO to BP3 | -0.5 | +7.5 | V |
| 1 | input current |  | -10 | +10 | mA |
| $\mathrm{l}_{0}$ | output current |  | -10 | +10 | mA |
| $\mathrm{I}_{\mathrm{DD}}$ | supply current |  | -50 | +50 | mA |
| $\mathrm{I}_{\mathrm{DD}(\mathrm{LCD})}$ | LCD supply current |  | -50 | +50 | mA |
| Iss | ground supply current |  | -50 | +50 | mA |
| $\mathrm{P}_{\text {tot }}$ | total power dissipation |  | - | 400 | mW |
| $\mathrm{P}_{0}$ | output power |  | - | 100 | mW |
| $V_{\text {ESD }}$ | electrostatic discharge voltage | HBM | [1] - | $\pm 5000$ | V |
|  |  | MM | [2] - | $\pm 200$ | V |
|  |  | CDM | [3] - | $\pm 1000$ | V |
| $\mathrm{I}_{\text {u }}$ | latch-up current |  | [4] - | 100 | mA |
| $\mathrm{T}_{\text {stg }}$ | storage temperature |  | [5] -65 | +150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {amb }}$ | ambient temperature |  | -40 | +85 | ${ }^{\circ} \mathrm{C}$ |

[1] Pass level; Human Body Model (HBM) according to Ref. 7 "JESD22-A114".
[2] Pass level; Machine Model (MM), according to Ref. 8 "JESD22-A115".
[3] Pass level; Charged-Device Model (CDM), according to Ref. 9 "JESD22-C101".
[4] Pass level; latch-up testing according to Ref. 10 "JESD78" at maximum ambient temperature ( $\mathrm{T}_{\text {amb(max) }}$ ).
[5] According to the NXP store and transport requirements (see Ref. 12 "NX3-00092") the devices have to be stored at a temperature of $+8{ }^{\circ} \mathrm{C}$ to $+45^{\circ} \mathrm{C}$ and a humidity of $25 \%$ to $75 \%$. For long-term storage products, divergent conditions are described in that document.

## 10. Static characteristics

Table 15. Static characteristics
$V_{D D}=1.8 \mathrm{~V}$ to $5.5 \mathrm{~V} ; V_{S S}=0 \mathrm{~V} ; V_{L C D}=2.5 \mathrm{~V}$ to $6.5 \mathrm{~V} ; T_{\text {amb }}=-40^{\circ} \mathrm{C}$ to $+8{ }^{\circ} \mathrm{C}$; unless otherwise specified.

| Symbol | Parameter | Conditions |  | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Supplies |  |  |  |  |  |  |  |
| $V_{\text {DD }}$ | supply voltage |  |  | 1.8 | - | 5.5 | V |
| $V_{\text {LCD }}$ | LCD supply voltage |  | [1] | 2.5 | - | 6.5 | V |
| $\mathrm{I}_{\mathrm{DD}}$ | supply current | $\mathrm{f}_{\mathrm{clk}(\text { ext })}=1536 \mathrm{~Hz}$ | [2] | - | 6 | 20 | $\mu \mathrm{A}$ |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=3.0 \mathrm{~V} ; \\ & \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C} \end{aligned}$ |  | - | 2.7 | - | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\mathrm{DD}(\mathrm{LCD})}$ | LCD supply current | $\mathrm{f}_{\text {clk(ext) }}=1536 \mathrm{~Hz}$ | [2] | - | 18 | 30 | $\mu \mathrm{A}$ |
|  |  | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}(\mathrm{LCD})}=3.0 \mathrm{~V} ; \\ & \mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C} \end{aligned}$ |  | - | 17.5 | - | $\mu \mathrm{A}$ |
| Logic |  |  |  |  |  |  |  |
| $\mathrm{V}_{\text {P(POR) }}$ | power-on reset supply voltage |  |  | 1.0 | 1.3 | 1.6 | V |
| $\mathrm{V}_{\text {IL }}$ | LOW-level input voltage | on pins CLK, $\overline{\mathrm{SYNC}}$, OSC, A0 to A2, SA0, SCL, SDA |  | $\mathrm{V}_{\text {SS }}$ | - | $0.3 \mathrm{~V}_{\text {DD }}$ | V |
| $\mathrm{V}_{\mathrm{IH}}$ | HIGH-level input voltage | on pins CLK, $\overline{\text { SYNC, }}$ OSC, A0 to A2, SAO, SCL, SDA | [3][4] | $0.7 V_{\text {DD }}$ | - | $V_{D D}$ | V |
| $\mathrm{l}_{\text {OL }}$ | LOW-level output current | output sink current; $\mathrm{V}_{\mathrm{OL}}=0.4 \mathrm{~V} ; \mathrm{V}_{\mathrm{DD}}=5 \mathrm{~V}$ |  |  |  |  |  |
|  |  | on pins CLK and $\overline{\text { SYNC }}$ |  | 1 | - | - | mA |
|  |  | on pin SDA |  | 3 | - | - | mA |
| $\mathrm{IOH}_{\text {(CLK }}$ ) | HIGH-level output current on pin CLK | output source current; $\mathrm{V}_{\mathrm{OH}}=4.6 \mathrm{~V} ; \mathrm{V}_{\mathrm{DD}}=5 \mathrm{~V}$ |  | 1 | - | - | mA |
| $\mathrm{I}_{\mathrm{L}}$ | leakage current | $\begin{aligned} & V_{1}=V_{D D} \text { or } V_{S S} ; \\ & \text { on pins CLK, SCL, SDA, } \\ & \text { A0 to } A 2 \text { and } S A 0 \end{aligned}$ |  | -1 | - | +1 | $\mu \mathrm{A}$ |
| $\mathrm{I}_{\text {L(OSC) }}$ | leakage current on pin OSC | $V_{l}=V_{D D}$ |  | -1 | - | +1 | $\mu \mathrm{A}$ |
| $\mathrm{C}_{1}$ | input capacitance |  | [5] | - | - | 7 | pF |
| LCD outputs |  |  |  |  |  |  |  |
| $\Delta \mathrm{V}_{\mathrm{O}}$ | output voltage variation | on pins BP0 to BP3 and S0 to S39 |  | -100 | - | +100 | mV |
| $\mathrm{R}_{\mathrm{O}}$ | output resistance | $\mathrm{V}_{\text {LCD }}=5 \mathrm{~V}$ | [6] |  |  |  |  |
|  |  | on pins BP0 to BP3 |  | - | 1.5 | - | $\mathrm{k} \Omega$ |
|  |  | on pins S0 to S39 |  | - | 6.0 | - | k $\Omega$ |

[1] $\mathrm{V}_{\mathrm{LCD}}>3 \vee$ for $1 / 3$ bias.
[2] LCD outputs are open-circuit; inputs at $\mathrm{V}_{\mathrm{SS}}$ or $\mathrm{V}_{\mathrm{DD}}$; external clock with $50 \%$ duty factor; $\mathrm{I}^{2} \mathrm{C}$-bus inactive.
[3] When tested, $I^{2} \mathrm{C}$ pins SCL and SDA have no diode to $\mathrm{V}_{\mathrm{DD}}$ and may be driven to the $\mathrm{V}_{\mathrm{l}}$ limiting values given in Table 14 (see Figure 19 too).
[4] Propagation delay of driver between clock (CLK) and LCD driving signals.
[5] Periodically sampled, not $100 \%$ tested.
[6] Outputs measured one at a time.

## 11. Dynamic characteristics

Table 16. Dynamic characteristics
$V_{D D}=1.8 \mathrm{~V}$ to $5.5 \mathrm{~V} ; V_{S S}=0 \mathrm{~V} ; V_{L C D}=2.5 \mathrm{~V}$ to $6.5 \mathrm{~V} ; T_{\text {amb }}=-40^{\circ} \mathrm{C}$ to $+85{ }^{\circ} \mathrm{C}$; unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Clock |  |  |  |  |  |  |
| $\mathrm{f}_{\text {clk(int) }}$ | internal clock frequency | [1] | 1440 | 1850 | 2640 | Hz |
| $\mathrm{f}_{\text {clk(ext) }}$ | external clock frequency |  | 960 | - | 2640 | Hz |
| $\mathrm{t}_{\mathrm{clk}}$ (H) | HIGH-level clock time |  | 60 | - | - | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\mathrm{clk}(\mathrm{L})}$ | LOW-level clock time |  | 60 | - | - | $\mu \mathrm{S}$ |
| Synchronization |  |  |  |  |  |  |
| tPD(SYNC_N) | $\overline{\text { SYNC }}$ propagation delay |  | - | 30 | - | ns |
| tSYNC_NL | $\overline{\text { SYNC LOW time }}$ |  | 1 | - | - | $\mu \mathrm{S}$ |
| $t_{\text {PD (drv) }}$ | driver propagation delay | $\mathrm{V}_{\mathrm{LCD}}=5 \mathrm{~V} \quad \underline{[2]}$ | - | - | 30 | $\mu \mathrm{S}$ |
| $I^{2} \mathrm{C}$-bus ${ }^{\text {[3] }}$ |  |  |  |  |  |  |
| Pin SCL |  |  |  |  |  |  |
| $\mathrm{f}_{\text {SCL }}$ | SCL clock frequency |  | - | - | 400 | kHz |
| t LOW | LOW period of the SCL clock |  | 1.3 | - | - | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\text {HIGH }}$ | HIGH period of the SCL clock |  | 0.6 | - | - | $\mu \mathrm{S}$ |
| Pin SDA |  |  |  |  |  |  |
| $\mathrm{t}_{\text {SU; DAT }}$ | data set-up time |  | 100 | - | - | ns |
| $t_{\text {HD; DAT }}$ | data hold time |  | 0 | - | - | ns |
| Pins SCL and SDA |  |  |  |  |  |  |
| $t_{\text {BUF }}$ | bus free time between a STOP and START condition |  | 1.3 | - | - | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\text {SU; STO }}$ | set-up time for STOP condition |  | 0.6 | - | - | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\text {HD } ; \text { STA }}$ | hold time (repeated) START condition |  | 0.6 | - | - | $\mu \mathrm{S}$ |
| $t_{\text {SU; STA }}$ | set-up time for a repeated START condition |  | 0.6 | - | - | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\mathrm{r}}$ | rise time of both SDA and SCL signals | $\mathrm{f}_{\mathrm{SCL}}=400 \mathrm{kHz}$ | - | - | 0.3 | $\mu \mathrm{S}$ |
|  |  | $\mathrm{f}_{\text {SCL }}<125 \mathrm{kHz}$ | - | - | 1.0 | $\mu \mathrm{S}$ |
| $\mathrm{t}_{\mathrm{f}}$ | fall time of both SDA and SCL signals |  | - | - | 0.3 | $\mu \mathrm{S}$ |
| $\mathrm{C}_{\mathrm{b}}$ | capacitive load for each bus line |  | - | - | 400 | pF |
| $\mathrm{t}_{\text {w (spike) }}$ | spike pulse width | on the $\mathrm{I}^{2} \mathrm{C}$-bus | - | - | 50 | ns |

[1] Typical output duty factor: 50 \% measured at the CLK output pin.
[2] Not tested in production.
[3] All timing values are valid within the operating supply voltage and ambient temperature range and are referenced to $\mathrm{V}_{\mathrm{IL}}$ and $\mathrm{V}_{\mathrm{IH}}$ with an input voltage swing of $V_{S S}$ to $V_{D D}$.


Fig 20. Driver timing waveforms


Fig 21. $I^{2} \mathrm{C}$-bus timing waveforms

## 12. Application information

### 12.1 Cascaded operation

In large display configurations, up to 16 PCF8576Ds can be differentiated on the same ${ }^{2}$ 2 -bus by using the 3-bit hardware subaddresses (A0, A1 and A2) and the programmable $\mathrm{I}^{2} \mathrm{C}$-bus slave address (SA0).

Table 17. Addressing cascaded PCF8576D

| Cluster | Bit SAO | Pin 12 | Pin 11 | Pin A0 | Device |
| :---: | :---: | :---: | :---: | :---: | :---: |
| 1 | 0 | 0 | 0 | 0 | 0 |
|  |  | 0 | 0 | 1 | 1 |
|  |  | 0 | 1 | 0 | 2 |
|  |  | 0 | 1 | 1 | 3 |
|  |  | 1 | 0 | 0 | 4 |
|  |  | 1 | 0 | 1 | 5 |
|  |  | 1 | 1 | 0 | 6 |
|  |  | 1 | 1 | 1 | 7 |
| 2 | 1 | 0 | 0 | 0 | 8 |
|  |  | 0 | 0 | 1 | 9 |
|  |  | 0 | 1 | 0 | 10 |
|  |  | 0 | 1 | 1 | 11 |
|  |  | 1 | 0 | 0 | 12 |
|  |  | 1 | 0 | 1 | 13 |
|  |  | 1 | 1 | 0 | 14 |
|  |  | 1 | 1 | 1 | 15 |

PCF8576Ds connected in cascade are synchronized to allow the backplane signals from only one device in the cascade to be shared. This arrangement is cost-effective in large LCD applications since the backplane outputs of only one device need to be through-plated to the backplane electrodes of the display. The other cascaded PCF8576Ds contribute additional segment outputs but their backplane outputs are left open-circuit (see Figure 22).

All PCF8576Ds connected in cascade are correctly synchronized by the $\overline{\text { SYNC }}$ signal. This synchronization is guaranteed after the power-on reset. The only time that $\overline{\text { SYNC }}$ is likely to be needed is if synchronization is lost accidentally, for example, by noise in adverse electrical environments, or if the LCD multiplex drive mode is changed in an application using several cascaded PCF8576Ds, as the drive mode cannot be changed on all of the cascaded devices simultaneously. $\overline{\text { SYNC }}$ can be either an input or an output signal; a $\overline{\text { SYNC }}$ output is implemented as an open-drain driver with an internal pull-up resistor. The PCF8576D asserts $\overline{\text { SYNC }}$ at the start of its last active backplane signal and monitors the SYNC line at all other times. If cascade synchronization is lost, it is restored by the first PCF8576D to assert $\overline{\text { SYNC. The timing relationship between the backplane }}$ waveforms and the $\overline{\text { SYNC }}$ signal for each LCD drive mode is shown in Figure 23.

The contact resistance between the $\overline{\text { SYNC }}$ on each cascaded device must be controlled. If the resistance is too high, the device is not able to synchronize properly; this is particularly applicable to chip-on-glass applications. The maximum SYNC contact resistance allowed for the number of devices in cascade is given in Table 18.

Table 18. $\overline{\text { SYNC contact resistance }}$

| Number of devices | Maximum contact resistance |
| :--- | :--- |
| 2 | $6 \mathrm{k} \Omega$ |
| 3 to 5 | $2.2 \mathrm{k} \Omega$ |
| 6 to 10 | $1.2 \mathrm{k} \Omega$ |
| 10 to 16 | $700 \Omega$ |

The PCF8576D can be cascaded with the PCF8562, the PCF8533 or the PCF8534A. This allows optimal drive selection for a given number of pixels to display. Figure 20 and Figure 21 show the timing of the synchronization signals.


Fig 22. Cascaded PCF8576D configuration


Fig 23. Synchronization of the cascade for the various PCF8576D drive modes

## 13. Test information

The following quality information corresponds with the following product type: PCF8576DT/S400/2

### 13.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard Q100 - Failure mechanism based stress test qualification for integrated circuits, and is suitable for use in automotive applications.

## 14. Package outline



DIMENSIONS (mm are the original dimensions).

| UNIT | A max. | $\mathrm{A}_{1}$ | $\mathrm{A}_{2}$ | $\mathrm{A}_{3}$ | $\mathrm{b}_{\mathrm{p}}$ | c | $D^{(1)}$ | $E^{(2)}$ | e | $\mathrm{H}_{\mathrm{E}}$ | L | $L_{p}$ | Q | v | w | y | Z | $\theta$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| mm | 1.2 | $\begin{aligned} & 0.15 \\ & 0.05 \end{aligned}$ | $\begin{aligned} & 1.05 \\ & 0.85 \end{aligned}$ | 0.25 | $\begin{aligned} & 0.28 \\ & 0.17 \end{aligned}$ | $\begin{aligned} & 0.2 \\ & 0.1 \end{aligned}$ | $\begin{aligned} & \hline 14.1 \\ & 13.9 \end{aligned}$ | $\begin{aligned} & \hline 6.2 \\ & 6.0 \end{aligned}$ | 0.5 | $\begin{aligned} & \hline 8.3 \\ & 7.9 \end{aligned}$ | 1 | $\begin{aligned} & \hline 0.8 \\ & 0.4 \end{aligned}$ | $\begin{aligned} & 0.50 \\ & 0.35 \end{aligned}$ | 0.25 | 0.08 | 0.1 | $\begin{aligned} & \hline 0.5 \\ & 0.1 \end{aligned}$ | $8^{\circ}$ $0^{\circ}$ |

Notes

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

| OUTLINE <br> VERSION | REFERENCES |  |  |  | EUROPEAN <br> PROJECTION | ISSUE DATE |
| :--- | :---: | :---: | :---: | :---: | :---: | :---: |
|  | IEC | JEDEC | JEITA |  |  |  |
| SOT364-1 |  | MO-153 |  |  | - | $-9-12-27$ |

Fig 24. Package outline SOT364-1 (TSSOP56)

## 15. Bare die outline



Fig 25. Bare die outline PCF8576DU/DA/2 (for dimensions see Table 19)

detail X

detail Y

Notes

1. Marking code: PC8576D-2 pcf8576du_2da_do


Fig 26. Bare die outline PCF8576DU/2DA/2 (for dimensions see Table 20)

Table 19. Dimensions of PCF8576DU/DA/2 Original dimensions are in mm .

| Unit $(\mathbf{m m})$ | $\mathbf{A}$ | $\mathbf{D}$ | $\mathbf{E}$ | $\mathbf{e}^{[1]}$ | $\mathbf{P}_{\mathbf{1}}{ }^{[2]}$ | $\mathbf{P}_{\mathbf{2}}{ }^{[3]}$ | $\mathbf{P}_{\mathbf{3}}{ }^{[2]}$ | $\mathbf{P}_{\mathbf{4}}{ }^{[3]}$ |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| $\max$ | - | - | - | - | - | - | - | - |
| nom | 0.38 | 2.2 | 2.0 | - | 0.09 | 0.08 | 0.066 | 0.056 |
| $\min$ | - | - | - | 0.072 | - | - | - | - |

[1] Dimension not drawn to scale.
[2] Pad size.
[3] Passivation opening.

Table 20. Dimensions of PCF8576DU/2DA/2 Original dimensions are in mm.

| Unit (mm) | $\mathbf{A}$ | $\mathbf{A}_{\mathbf{1}}$ | $\mathbf{A}_{\mathbf{2}}$ | $\mathbf{b}$ | $\mathbf{D}$ | $\mathbf{E}$ | $\mathbf{e}^{[1]}$ | $\mathbf{L}$ |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| $\max$ | - | - | - | - | - | - | - | - |
| nom | 0.40 | 0.015 | 0.381 | 0.052 | 2.2 | 2.0 | - | 0.077 |
| $\min$ | - | - | - | - | - | - | 0.072 | - |

[1] Dimension not drawn to scale.

Table 21. Bonding pad location for PCF8576DU/x
All x/y coordinates represent the position of the center of each pad with respect to the center $(x / y=0)$ of the chip (see Figure 3, Figure 25 and Figure 26).

| Symbol | Pad | $\mathbf{X}(\mu \mathrm{m})$ | $\mathbf{Y}(\mu \mathrm{m})$ | Description |
| :--- | :--- | :--- | :--- | :--- |
| SDA | 1 | -34.38 | -876.6 | I $^{2}$ C-bus serial data input/output |
| SCL | 2 | 109.53 | -876.6 | I $^{2}$ C-bus serial clock input |
| SCL | 3 | 181.53 | -876.6 |  |
| SYNC | 4 | 365.58 | -876.6 | cascade synchronization input/output |
| CLK | 5 | 469.08 | -876.6 | external clock input/output |
| VDD | 6 | 577.08 | -876.6 | supply voltage |
| OSC | 7 | 740.88 | -876.6 | internal oscillator enable input |
| A0 | 8 | 835.83 | -876.6 | subaddress inputs |
| A1 | 9 | 1005.48 | -630.9 |  |
| A2 | 10 | 1005.48 | -513.9 |  |
| SA0 | 11 | 1005.48 | -396.9 | I $^{2}$ C-bus address input; bit 0 |
| VSS | 12 | 1005.48 | -221.4 | ground supply voltage |
| VLCD | 13 | 1005.48 | 10.71 | LCD supply voltage |
| BP0 | 14 | 1005.48 | 156.51 | LCD backplane outputs |
| BP2 | 15 | 1005.48 | 232.74 |  |
| BP1 | 16 | 1005.48 | 308.97 |  |
| BP3 | 17 | 1005.48 | 385.2 |  |
| S0 | 18 | 1005.48 | 493.2 | LCD segment outputs |
| S1 | 19 | 1005.48 | 565.2 |  |
| S2 | 20 | 1005.48 | 637.2 |  |
| S3 | 21 | 1005.48 | 709.2 |  |

Table 21. Bonding pad location for PCF8576DU/x ...continued All $x / y$ coordinates represent the position of the center of each pad with respect to the center $(x / y=0)$ of the chip (see Figure 3, Figure 25 and Figure 26).

| Symbol | Pad | X ( $\mu \mathrm{m}$ ) | $\mathrm{Y}(\mu \mathrm{m})$ | Description |
| :---: | :---: | :---: | :---: | :---: |
| S4 | 22 | 347.22 | 876.6 | LCD segment outputs |
| S5 | 23 | 263.97 | 876.6 |  |
| S6 | 24 | 180.72 | 876.6 |  |
| S7 | 25 | 97.47 | 876.6 |  |
| S8 | 26 | 14.22 | 876.6 |  |
| S9 | 27 | -69.03 | 876.6 |  |
| S10 | 28 | -152.28 | 876.6 |  |
| S11 | 29 | -235.53 | 876.6 |  |
| S12 | 30 | -318.78 | 876.6 |  |
| S13 | 31 | -402.03 | 876.6 |  |
| S14 | 32 | -485.28 | 876.6 |  |
| S15 | 33 | -568.53 | 876.6 |  |
| S16 | 34 | -651.78 | 876.6 |  |
| S17 | 35 | -735.03 | 876.6 |  |
| S18 | 36 | -1005.5 | 625.59 |  |
| S19 | 37 | -1005.5 | 541.62 |  |
| S20 | 38 | -1005.5 | 458.19 |  |
| S21 | 39 | -1005.5 | 374.76 |  |
| S22 | 40 | -1005.5 | 291.33 |  |
| S23 | 41 | -1005.5 | 207.9 |  |
| S24 | 42 | -1005.5 | 124.47 |  |
| S25 | 43 | -1005.5 | 41.04 |  |
| S26 | 44 | -1005.5 | -42.39 |  |
| S27 | 45 | -1005.5 | -125.8 |  |
| S28 | 46 | -1005.5 | -209.3 |  |
| S29 | 47 | -1005.5 | -292.7 |  |
| S30 | 48 | -1005.5 | -376.1 |  |
| S31 | 49 | -1005.5 | -459.5 |  |
| S32 | 50 | -1005.5 | -543 |  |
| S33 | 51 | -1005.5 | -625.6 |  |
| S34 | 52 | -735.03 | -876.6 |  |
| S35 | 53 | -663.03 | -876.6 |  |
| S36 | 54 | -591.03 | -876.6 |  |
| S37 | 55 | -519.03 | -876.6 |  |
| S38 | 56 | -447.03 | -876.6 |  |

Table 21. Bonding pad location for PCF8576DU/x ...continued All x/y coordinates represent the position of the center of each pad with respect to the center $(x / y=0)$ of the chip (see Figure 3, Figure 25 and Figure 26).

| Symbol | Pad | $\mathbf{X}(\mu \mathrm{m})$ | $\mathbf{Y}(\mu \mathrm{m})$ | Description |
| :--- | :--- | :--- | :--- | :--- |
| S39 | 57 | -375.03 | -876.6 | LCD segment outputs |
| SDA | 58 | -196.38 | -876.6 | I $^{2}$ C-bus serial data input/output |
| SDA | 59 | -106.38 | -876.6 |  |

Table 22. Alignment marks
All x/y coordinates represent the position of the center of each alignment mark with respect to the center $(x / y=0)$ of the chip (see Figure 3, Figure 25 and Figure 26).

| Symbol | $\mathbf{X}(\mu \mathrm{m})$ | $\mathbf{Y}(\mu \mathrm{m})$ |
| :--- | :--- | :--- |
| C1 | 930.42 | -870.3 |
| C2 | -829.98 | -870.3 |

## 16. Handling information

All input and output pins are protected against ElectroStatic Discharge (ESD) under normal handling. When handling Metal-Oxide Semiconductor (MOS) devices ensure that all normal precautions are taken as described in JESD625-A, IEC 61340-5 or equivalent standards.

## 17. Packing information

### 17.1 Tray information



Fig 27. Tray details

Table 23. Tray dimensions (see Figure 27)

| Symbol | Description | Value | Unit |
| :--- | :--- | :--- | :--- |
| A | pocket pitch in $x$ direction | 5.59 | mm |
| B | pocket pitch in $y$ direction | 6.35 | mm |
| C | pocket width in $x$ direction | 3.16 | mm |
| D | pocket width in $y$ direction | 3.16 | mm |
| E | tray width in $x$ direction | 50.8 | mm |
| F | tray width in $y$ direction | 50.8 | mm |
| G | cut corner to pocket 1.1 center | 5.83 | mm |
| H | cut corner to pocket 1.1 center | 6.35 | mm |
| X | number of pockets, x direction | 8 | - |
| y | number of pockets, y direction | 7 | - |



Fig 28. Tray alignment

### 17.2 Carrier tape information



001aaj314
Fig 29. Tape details

Table 24. Carrier tape dimensions

| Symbol | Description | Value | Unit |
| :--- | :--- | :--- | :--- |
| A0 | pocket width in $x$ direction | 8.6 | mm |
| B0 | pocket width in $y$ direction | 14.5 | mm |
| K0 | pocket height | 1.8 | mm |
| P1 | sprocket hole pitch | 12 | mm |
| W | tape width in y direction | 24 | mm |

## 18. Soldering of SMD packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note AN10365 "Surface mount reflow soldering description".

### 18.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

### 18.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leaded or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leaded SMDs with leads having a pitch smaller than $\sim 0.6 \mathrm{~mm}$ cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leaded packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- Board specifications, including the board finish, solder masks and vias
- Package footprints, including solder thieves and orientation
- The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus SnPb soldering


### 18.3 Wave soldering

Key characteristics in wave soldering are:

- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- Solder bath specifications, including temperature and impurities


### 18.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see Figure 30) than a SnPb process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with Table 25 and 26

Table 25. SnPb eutectic process (from J-STD-020C)

| Package thickness (mm) | Package reflow temperature $\left({ }^{\circ} \mathrm{C}\right)$ |  |
| :--- | :--- | :--- |
|  | Volume $\left(\mathbf{m m}^{\mathbf{3}}\right)$ |  |
|  | $<350$ | $\geq 350$ |
| $<2.5$ | 235 | 220 |
| $\geq 2.5$ | 220 | 220 |

Table 26. Lead-free process (from J-STD-020C)

| Package thickness (mm) | Package reflow temperature ( ${ }^{\circ} \mathrm{C}$ ) |  |  |  |
| :--- | :--- | :--- | :---: | :---: |
|  | Volume $\left(\mathbf{m m}^{\mathbf{3}}\right)$ |  |  |  |
|  | $<\mathbf{3 5 0}$ | $\mathbf{3 5 0}$ to $\mathbf{2 0 0 0}$ |  |  |
| $<1.6$ | 260 | 260 |  |  |
| $\mathbf{2 0 0 0}$ |  |  |  |  |
| 1.6 to 2.5 | 260 | 250 |  |  |
| $>2.5$ | 250 | 245 |  |  |

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see Figure 30.


MSL: Moisture Sensitivity Level
Fig 30. Temperature profiles for large and small components
For further information on temperature profiles, refer to Application Note AN10365 "Surface mount reflow soldering description".

Table 27. Abbreviations

| Acronym | Description |
| :--- | :--- |
| CDM | Charged-Device Model |
| CMOS | Complementary Metal-Oxide Semiconductor |
| HBM | Human Body Model |
| ITO | Indium Tin Oxide |
| LCD | Liquid Crystal Display |
| LSB | Least Significant Bit |
| MM | Machine Model |
| MSB | Most Significant Bit |
| MSL | Moisture Sensitivity Level |
| PCB | Printed Circuit Board |
| RAM | Random Access Memory |
| RMS | Root Mean Square |
| SCL | Serial CLock line |
| SDA | Serial DAta line |
| SMD | Surface Mount Device |

## 20. References

[1] AN10170 - Design guidelines for COG modules with NXP monochrome LCD drivers
[2] AN10365 - Surface mount reflow soldering description
[3] AN10706 - Handling bare die
[4] IEC 60134 - Rating systems for electronic tubes and valves and analogous semiconductor devices
[5] IEC 61340-5 - Protection of electronic devices from electrostatic phenomena
[6] IPCIJEDEC J-STD-020D - Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices
[7] JESD22-A114 - Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)
[8] JESD22-A115 — Electrostatic Discharge (ESD) Sensitivity Testing Machine Model (MM)
[9] JESD22-C101 — Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components
[10] JESD78 — IC Latch-Up Test
[11] JESD625-A — Requirements for Handling Electrostatic-Discharge-Sensitive (ESDS) Devices
[12] NX3-00092 - NXP store and transport requirements
[13] UM10204 - $I^{2}$ C-bus specification and user manual

## 21. Revision history

Table 28. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
| :---: | :---: | :---: | :---: | :---: |
| PCF8576D v. 10 | 20110214 | Product data sheet | - | PCF8576D_9 |
| Modifications: | - Adjusted die size <br> - Removed product type PCF8576DH/2 <br> - Adjusted values of $\mathrm{I}_{\mathrm{DD}}$ and $\mathrm{I}_{\mathrm{DD}(\mathrm{LCD})}$ in Table 15 <br> - Deleted power-on remark in Section 7.5.1 |  |  |  |
| PCF8576D_9 | 20090825 | Product data sheet | - | PCF8576D_8 |
| PCF8576D_8 | 20090319 | Product data sheet | - | PCF8576D_7 |
| PCF8576D_7 | 20081218 | Product data sheet | - | PCF8576D_6 |
| PCF8576D_6 | 20081202 | Product data sheet | - | PCF8576D_5 |
| PCF8576D_5 | 20041222 | Product specification | - | PCF8576D_4 |
| PCF8576D_4 | 20041008 | Product specification | - | PCF8576D_3 |
| PCF8576D_3 | 20040617 | Product specification | - | PCF8576D_2 |
| PCF8576D_2 | 20030623 | Product specification | - | PCF8576D_1 |
| PCF8576D_1 | 20030401 | Objective specification | - | - |

## 22. Legal information

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| Document status $\underline{[1][2]}$ | Product status르 | Definition |
| :--- | :--- | :--- |
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| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
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